

# **TONY CHAPMAN ELECTRONICS**

## **Device Characterisation Seminar**

Glasgow university,  
Room 514, Rankine Building,  
Department of Electronics and Electrical Engineering.  
Oakfield Avenue.

**24<sup>th</sup> February, 2010 10.00 – 11.30 am:**

### **Solutions for Precise On-wafer IV, CV and r.f. measurements to 325GHz – Gavin Fisher - Cascade Microtech Inc**

It is essential that a set of proven tools and techniques are readily available to make accurate and repeatable measurements from DC to 325GHz, thus allowing precise characterisation of the device. This paper covers the typical on-wafer solutions, the tools that are incorporated and the techniques that are recommended for successful on-wafer measurements.

**Buffet Lunch: 11.30am**

**For further information and reservation, please contact:**

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